# Dual Operational Transconductance Amplifier

The AU5517 and NE5517 contain two current-controlled transconductance amplifiers, each with a differential input and push-pull output. The AU5517/NE5517 offers significant design and performance advantages over similar devices for all types of programmable gain applications. Circuit performance is enhanced through the use of linearizing diodes at the inputs which enable a 10 dB signal-to-noise improvement referenced to 0.5% THD. The AU5517/NE5517 is suited for a wide variety of industrial and consumer applications.

Constant impedance of the buffers on the chip allow general use of the AU5517/NE5517. These buffers are made of Darlington transistors and a biasing network that virtually eliminate the change of offset voltage due to a burst in the bias current  $I_{ABC}$ , hence eliminating the audible noise that could otherwise be heard in high quality audio applications.

#### Features

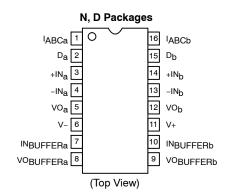
- Constant Impedance Buffers
- $\Delta V_{BE}$  of Buffer is Constant with Amplifier I<sub>BIAS</sub> Change
- Excellent Matching Between Amplifiers
- Linearizing Diodes
- High Output Signal-to-Noise Ratio
- Pb-Free Packages are Available\*

#### Applications

- Multiplexers
- Timers
- Electronic Music Synthesizers
- Dolby® HX Systems
- Current-Controlled Amplifiers, Filters
- Current-Controlled Oscillators, Impedances

ON Semiconductor®			
http://onse	mi.com		
	MARKING DIAGRAMS		
1 D SUFFIX CASE 751B	A A A A A A A A A A A A A A A A A A A		
PDIP-16 N SUFFIX CASE 648	<u>እድንግንም የተተታለቀዋ በ</u> NE5517yy O AWLYYWWG የየምምምምም		
xx = AU or N yy = AN or N A = Assemb WL = Wafer L YY, Y = Year WW = Work W G = Pb-Free	l bly Location ot /eek		

#### **PIN CONNECTIONS**



#### **ORDERING INFORMATION**

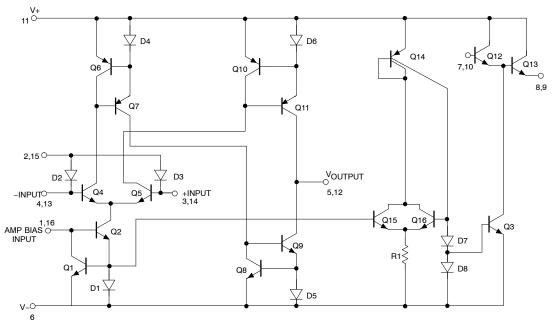
See detailed ordering and shipping information in the package dimensions section on page 13 of this data sheet.

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

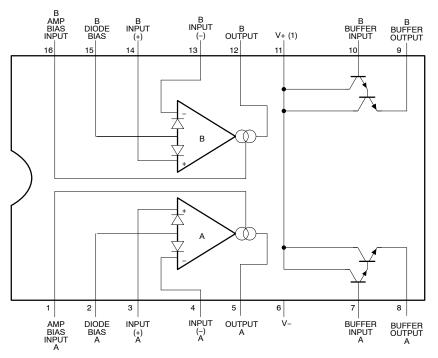
Semiconductor Components Industries, LLC, 2013 June, 2013 – Rev. 4

## **PIN DESCRIPTION**

Pin No.	Symbol	Description
1	I <sub>ABCa</sub>	Amplifier Bias Input A
2	Da	Diode Bias A
3	+IN <sub>a</sub>	Non-inverted Input A
4	-IN <sub>a</sub>	Inverted Input A
5	VOa	Output A
6	V-	Negative Supply
7	IN <sub>BUFFERa</sub>	Buffer Input A
8	VO <sub>BUFFERa</sub>	Buffer Output A
9	VO <sub>BUFFERb</sub>	Buffer Output B
10	IN <sub>BUFFERb</sub>	Buffer Input B
11	V+	Positive Supply
12	VOb	Output B
13	–IN <sub>b</sub>	Inverted Input B
14	+IN <sub>b</sub>	Non-inverted Input B
15	D <sub>b</sub>	Diode Bias B
16	I <sub>ABCb</sub>	Amplifier Bias Input B







NOTE: V+ of output buffers and amplifiers are internally connected.

Figure 2. Connection Diagram

#### MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Supply Voltage (Note 1)	V <sub>S</sub>	44 V <sub>DC</sub> or ±22	V
Power Dissipation, T <sub>amb</sub> = 25 °C (Still Air) (Note 2) NE5517N, NE5517AN NE5517D, AU5517D	PD	1500 1125	mW
Thermal Resistance, Junction-to-Ambient D Package N Package	R <sub>θJA</sub>	140 94	°C/W
Differential Input Voltage	V <sub>IN</sub>	±5.0	V
Diode Bias Current	۱ <sub>D</sub>	2.0	mA
Amplifier Bias Current	I <sub>ABC</sub>	2.0	mA
Output Short-Circuit Duration	I <sub>SC</sub>	Indefinite	
Buffer Output Current (Note 3)	I <sub>OUT</sub>	20	mA
Operating Temperature Range NE5517N, NE5517AN AU5517T	T <sub>amb</sub>	0 °C to +70 °C -40 °C to +125 °C	°C
Operating Junction Temperature	TJ	150	°C
DC Input Voltage	V <sub>DC</sub>	$+V_{S}$ to $-V_{S}$	
Storage Temperature Range	T <sub>stg</sub>	–65 °C to +150 °C	°C
Lead Soldering Temperature (10 sec max)	T <sub>sld</sub>	230	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. For selections to a supply voltage above ±22 V, contact factory.

2. The following derating factors should be applied above 25  $^\circ\mathrm{C}$ 

N package at 10.6 mW/°C D package at 7.1 mW/°C.

3. Buffer output current should be limited so as to not exceed package dissipation.

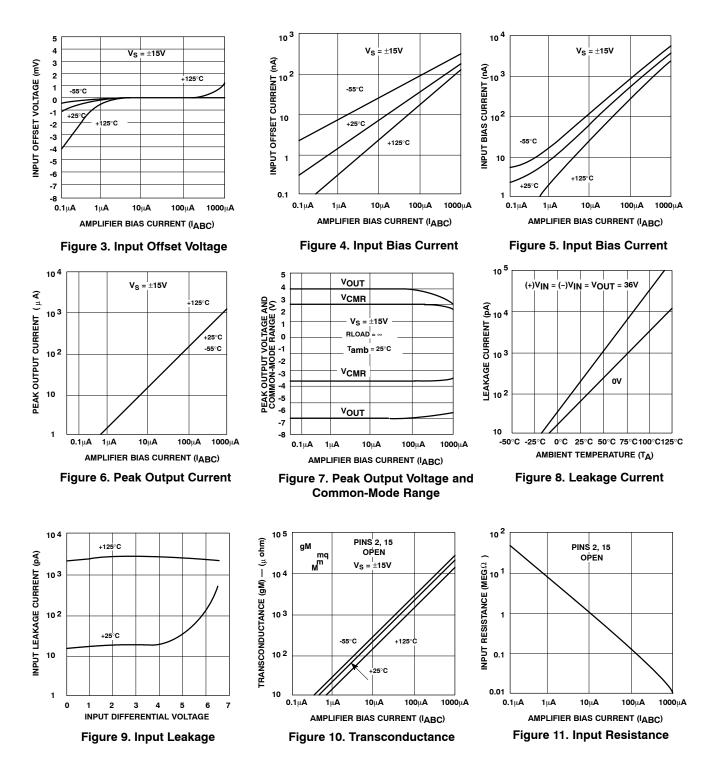
#### **ELECTRICAL CHARACTERISTICS** (Note 4)

			AU5517/NE5517			NE5517A			
Characteristic	Test Conditions	Symbol	Min	Тур	Max	Min	Тур	Max	Unit
Input Offset Voltage	Overtemperature Range	V <sub>OS</sub>		0.4	5.0 5.0		0.4	2.0 5.0	mV
N/ //T	I <sub>ABC</sub> 5.0 μA			0.3	5.0		0.3	2.0	
$\Delta V_{OS} / \Delta T$	Avg. TC of Input Offset Voltage			7.0	_		7.0		μV/°C
V <sub>OS</sub> Including Diodes	Diode Bias Current (I <sub>D</sub> ) = 500 μA			0.5	5		0.5	2.0	mV
Input Offset Change	5.0 $\mu$ A $\leq$ I <sub>ABC</sub> $\leq$ 500 $\mu$ A	V <sub>OS</sub>		0.1			0.1	3.0	mV
Input Offset Current		I <sub>OS</sub>		0.1	0.6		0.1	0.6	μA
$\Delta I_{OS} / \Delta T$	Avg. TC of Input Offset Current			0.001			0.001		μA/°C
Input Bias Current	Overtemperature Range	I <sub>BIAS</sub>		0.4 1.0	5.0 8.0		0.4 1.0	5.0 7.0	μΑ
$\Delta I_{B} / \Delta T$	Avg. TC of Input Current			0.01			0.01		μA/°C
Forward Transconductance	Overtemperature Range	9м	6700 5400	9600	13000	7700 4000	9600	12000	μmho
g <sub>M</sub> Tracking				0.3			0.3		dB
Peak Output Current	$\begin{array}{c} R_L=0, \ I_{ABC}=5.0 \ \mu A \\ R_L=0, \ I_{ABC}=500 \ \mu A \\ R_L=0, \ Overtemperature \\ Range \end{array}$	I <sub>OUT</sub>	350 300	5.0 500	650	3.0 350 300	5.0 500	7.0 650	μA
Peak Output Voltage Positive Negative	$ \begin{array}{l} R_L = \infty, \ 5.0 \ \mu A \leq I_{ABC} \leq 500 \ \mu A \\ R_L = \infty, \ 5.0 \ \mu A \leq I_{ABC} \leq 500 \ \mu A \end{array} $	V <sub>OUT</sub>	+12 -12	+14.2 -14.4		+12 -12	+14.2 -14.4		V
Supply Current	$I_{ABC}$ = 500 $\mu$ A, both channels	I <sub>CC</sub>		2.6	4.0		2.6	4.0	mA
V <sub>OS</sub> Sensitivity Positive Negative	$\Delta$ V <sub>OS</sub> / $\Delta$ V+ $\Delta$ V <sub>OS</sub> / $\Delta$ V-			20 20	150 150		20 20	150 150	μV/V
Common-mode Rejection Ration		CMRR	80	110		80	110		dB
Common-mode Range			±12	±13.5		±12	±13.5		V
Crosstalk	Referred to Input (Note 5) 20 Hz < f < 20 kHz			100			100		dB
Differential Input Current	I <sub>ABC</sub> = 0, Input = ±4.0 V	l <sub>IN</sub>		0.02	100		0.02	10	nA
Leakage Current	I <sub>ABC</sub> = 0 (Refer to Test Circuit)			0.2	100		0.2	5.0	nA
Input Resistance		R <sub>IN</sub>	10	26		10	26		kΩ
Open-loop Bandwidth		B <sub>W</sub>		2.0			2.0		MHz
Slew Rate	Unity Gain Compensated	SR		50			50		V/μs
Buffer Input Current	5	IN <sub>BUFFER</sub>		0.4	5.0		0.4	5.0	μA
Peak Buffer Output Voltage	5	VO <sub>BUFFER</sub>	10			10			V
$\Delta V_{BE}$ of Buffer	Refer to Buffer V <sub>BE</sub> Test Circuit (Note 6)			0.5	5.0		0.5	5.0	mV

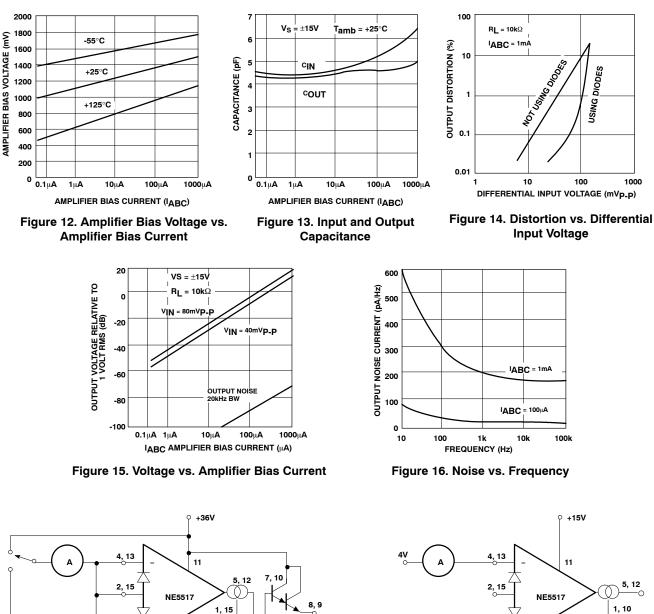
4. These specifications apply for V<sub>S</sub> = ±15 V, T<sub>amb</sub> = 25°C, amplifier bias current (I<sub>ABC</sub>) = 500 μA, Pins 2 and 15 open unless otherwise specified. The inputs to the buffers are grounded and outputs are open.
5. These specifications apply for V<sub>S</sub> = ±15 V, I<sub>ABC</sub> = 500 μA, R<sub>OUT</sub> = 5.0 kΩ connected from the buffer output to -V<sub>S</sub> and the input of the buffer is connected to the transconductance amplifier output.

6. V<sub>S</sub> = ±15, R<sub>OUT</sub> = 5.0 k $\Omega$  connected from Buffer output to -V<sub>S</sub> and 5.0  $\mu$ A ≤ I<sub>ABC</sub> ≤ 500  $\mu$ A.

## **TYPICAL PERFORMANCE CHARACTERISTICS**



#### TYPICAL PERFORMANCE CHARACTERISTICS (continued)



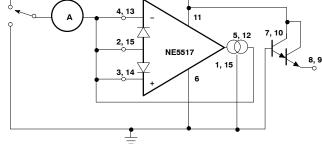
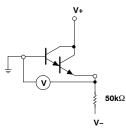


Figure 17. Leakage Current Test Circuit



з.

Figure 18. Differential Input Current Test Circuit

-

6

-15V

Figure 19. Buffer VBE Test Circuit

#### **APPLICATIONS**

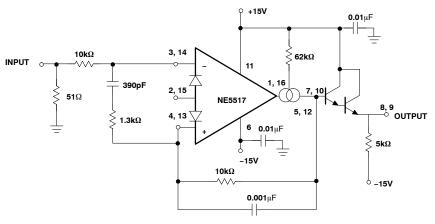


Figure 20. Unity Gain Follower

### **CIRCUIT DESCRIPTION**

The circuit schematic diagram of one-half of the AU5517/NE5517, a dual operational transconductance amplifier with linearizing diodes and impedance buffers, is shown in Figure 21.

#### Transconductance Amplifier

The transistor pair,  $Q_4$  and  $Q_5$ , forms a transconductance stage. The ratio of their collector currents ( $I_4$  and  $I_5$ , respectively) is defined by the differential input voltage,  $V_{IN}$ , which is shown in Equation 1.

$$V_{IN} = \frac{KT}{q} \ln \frac{I_5}{I_4}$$
 (eq. 1)

Where V<sub>IN</sub> is the difference of the two input voltages

 $KT \cong 26 \text{ mV}$  at room temperature (300°k).

Transistors  $Q_1$ ,  $Q_2$  and diode  $D_1$  form a current mirror which focuses the sum of current  $I_4$  and  $I_5$  to be equal to amplifier bias current  $I_B$ :

$$I_4 + I_5 = I_B \tag{eq. 2}$$

If  $V_{IN}$  is small, the ratio of  $I_5$  and  $I_4$  will approach unity and the Taylor series of In function can be approximated as

$$\begin{array}{l} \frac{\text{KT}}{\text{q}} \, \ln \, \frac{\text{I}_5}{\text{I}_4} \approx \frac{\text{KT}}{\text{q}} \, \frac{\text{I}_5 - \text{I}_4}{\text{I}_4} \\ \\ \text{and} \, \text{I}_4 \cong \text{I}_5 \cong \text{I}_B \end{array} \tag{eq. 3}$$

$$\frac{\text{KT}}{\text{q}} \text{In} \frac{\text{I}_{5}}{\text{I}_{4}} \approx \frac{\text{KT}}{\text{q}} \frac{\text{I}_{5} - \text{I}_{4}}{1/2\text{I}_{\text{B}}} = \frac{2\text{KT}}{\text{q}} \frac{\text{I}_{5} - \text{I}_{4}}{\text{I}_{\text{B}}} = \text{V}_{\text{IN}} \quad (\text{eq. 4})$$
$$\text{I}_{5} - \text{I}_{4} = \text{V}_{\text{IN}} \frac{\left(\text{I}_{\text{B}}^{\text{q}}\right)}{2\text{KT}}$$

The remaining transistors ( $Q_6$  to  $Q_{11}$ ) and diodes ( $D_4$  to  $D_6$ ) form three current mirrors that produce an output current equal to  $I_5$  minus  $I_4$ . Thus:

$$V_{IN}\left(I_{B}\frac{q}{2KT}\right) = I_{O} \qquad (eq. 5)$$

The term  $\frac{(I_B^{q})}{2KT}$  is then the transconductance of the amplifier and is proportional to I<sub>B</sub>.

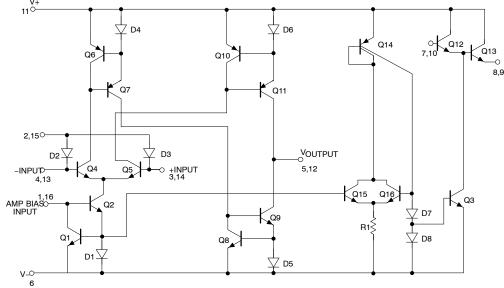


Figure 21. Circuit Diagram of NE5517

#### Linearizing Diodes

For V<sub>IN</sub> greater than a few millivolts, Equation 3 becomes invalid and the transconductance increases non-linearly. Figure 22 shows how the internal diodes can linearize the transfer function of the operational amplifier. Assume D<sub>2</sub> and D<sub>3</sub> are biased with current sources and the input signal current is I<sub>S</sub>. Since I<sub>4</sub> + I<sub>5</sub> = I<sub>B</sub> and I<sub>5</sub> - I<sub>4</sub> = I<sub>0</sub>, that is: I<sub>4</sub> = (I<sub>B</sub> - I<sub>0</sub>), I<sub>5</sub> = (I<sub>B</sub> + I<sub>0</sub>)

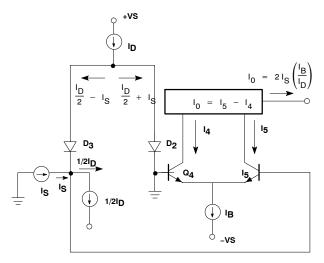


Figure 22. Linearizing Diode

For the diodes and the input transistors that have identical geometries and are subject to similar voltages and temperatures, the following equation is true:

$$\frac{T}{q} \ln \frac{\frac{I_D}{2} + I_S}{\frac{I_D}{2} - I_S} = \frac{KT}{q} \ln \frac{1/2(I_B + I_O)}{1/2(I_B - I_O)}$$
(eq. 6)  
$$I_O = I_S \frac{2IB}{I_D} \text{ for } |I_S| < \frac{I_D}{2}$$

The only limitation is that the signal current should not exceed  $I_D$ .

#### Impedance Buffer

The upper limit of transconductance is defined by the maximum value of  $I_B$  (2.0 mA). The lowest value of  $I_B$  for which the amplifier will function therefore determines the overall dynamic range. At low values of  $I_B$ , a buffer with very low input bias current is desired. A Darlington amplifier with constant-current source (Q<sub>14</sub>, Q<sub>15</sub>, Q<sub>16</sub>, D<sub>7</sub>, D<sub>8</sub>, and R<sub>1</sub>) suits the need.

#### APPLICATIONS

#### Voltage-Controlled Amplifier

In Figure 23, the voltage divider  $R_2$ ,  $R_3$  divides the input-voltage into small values (mV range) so the amplifier operates in a linear manner.

It is:

$$I_{OUT} = -V_{IN} \cdot \frac{R_3}{R_2 + R_3} \cdot g_M;$$
$$V_{OUT} = I_{OUT} \cdot R_L;$$
$$A = \frac{V_{OUT}}{V_{IN}} = \frac{R_3}{R_2 + R_3} \cdot g_M \cdot R_L$$
(3)  $g_M = 19.2 I_{ABC}$ (g<sub>M</sub> in µmhos for  $I_{ABC}$  in mA)

Since  $g_M$  is directly proportional to  $I_{ABC}$ , the amplification is controlled by the voltage  $V_C$  in a simple way.

When  $V_C$  is taken relative to  $-V_{CC}$  the following formula is valid:

$$\mathsf{I}_{\mathsf{ABC}} = \frac{(\mathsf{V}_{\mathsf{C}} - 1.2\mathsf{V})}{\mathsf{R}_1}$$

The 1.2 V is the voltage across two base-emitter baths in the current mirrors. This circuit is the base for many applications of the AU5517/NE5517.

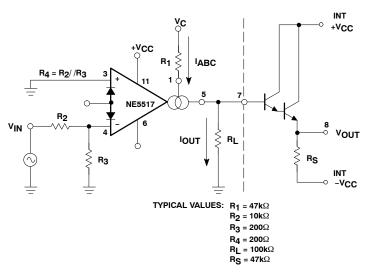


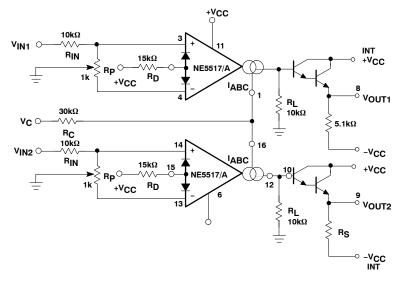
Figure 23.

#### **Stereo Amplifier With Gain Control**

Figure 24 shows a stereo amplifier with variable gain via a control input. Excellent tracking of typical 0.3 dB is easy to achieve. With the potentiometer,  $R_P$ , the offset can be adjusted. For AC-coupled amplifiers, the potentiometer may be replaced with two 510  $\Omega$  resistors.

#### Modulators

Because the transconductance of an OTA (Operational Transconductance Amplifier) is directly proportional to  $I_{ABC}$ , the amplification of a signal can be controlled easily. The output current is the product from transconductance×input voltage. The circuit is effective up to approximately 200 kHz. Modulation of 99% is easy to achieve.





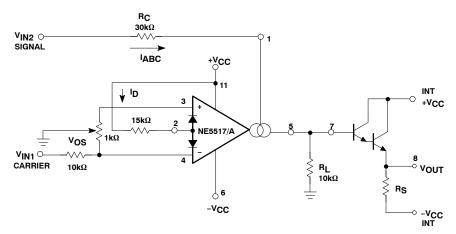


Figure 25. Amplitude Modulator

#### Voltage-Controlled Resistor (VCR)

Because an OTA is capable of producing an output current proportional to the input voltage, a voltage variable resistor can be made. Figure 26 shows how this is done. A voltage presented at the  $R_X$  terminals forces a voltage at the input. This voltage is multiplied by  $g_M$  and thereby forces a current through the  $R_X$  terminals:

$$R_x = \frac{R + R_A}{g_M + R_A}$$

where  $g_M$  is approximately 19.21  $\mu$ MHOs at room temperature. Figure 27 shows a Voltage Controlled Resistor using linearizing diodes. This improves the noise performance of the resistor.

#### **Voltage-Controlled Filters**

Figure 28 shows a Voltage Controlled Low-Pass Filter. The circuit is a unity gain buffer until  $X_C/g_M$  is equal to  $R/R_A$ . Then, the frequency response rolls off at a 6dB per octave with the -3 dB point being defined by the given equations. Operating in the same manner, a Voltage Controlled High-Pass Filter is shown in Figure 29. Higher order filters can be made using additional amplifiers as shown in Figures 30 and 31.

#### Voltage-Controlled Oscillators

Figure 32 shows a voltage-controlled triangle-square wave generator. With the indicated values a range from 2.0 Hz to 200 kHz is possible by varying  $I_{ABC}$  from 1.0 mA to 10  $\mu$ A.

The output amplitude is determined by  $I_{OUT} \times R_{OUT}$ .

Please notice the differential input voltage is not allowed to be above 5.0 V.

With a slight modification of this circuit you can get the sawtooth pulse generator, as shown in Figure 33.

#### **APPLICATION HINTS**

To hold the transconductance  $g_M$  within the linear range,  $I_{ABC}$  should be chosen not greater than 1.0 mA. The current mirror ratio should be as accurate as possible over the entire current range. A current mirror with only two transistors is not recommended. A suitable current mirror can be built with a PNP transistor array which causes excellent matching and thermal coupling among the transistors. The output current range of the DAC normally reaches from 0 to -2.0 mA. In this application, however, the current range is set through  $R_{REF}$  (10 k $\Omega$ ) to 0 to -1.0 mA.

$$I_{DACMAX} = 2 \cdot \frac{V_{REF}}{R_{REF}} = 2 \cdot \frac{5V}{10k\Omega} = 1mA$$

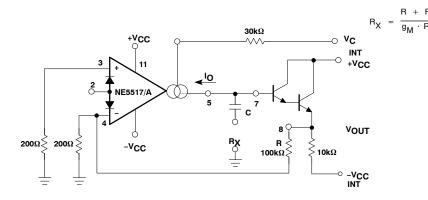


Figure 26. VCR

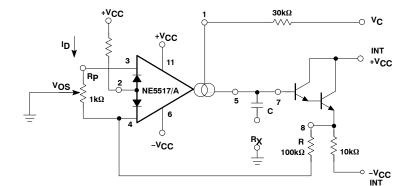
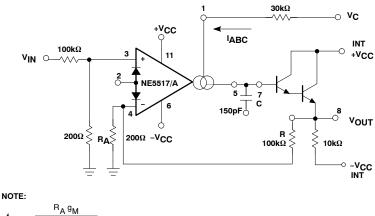
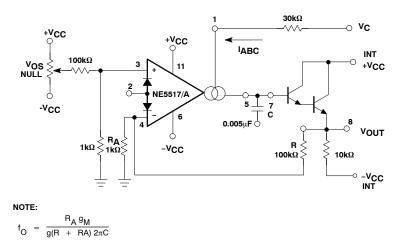


Figure 27. VCR with Linearizing Diodes



 $f_{O} = \frac{HA g_{M}}{g(R + RA) 2\pi C}$ 

Figure 28. Voltage-Controlled Low-Pass Filter





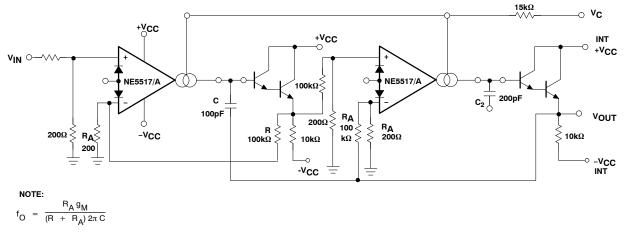


Figure 30. Butterworth Filter – 2nd Order

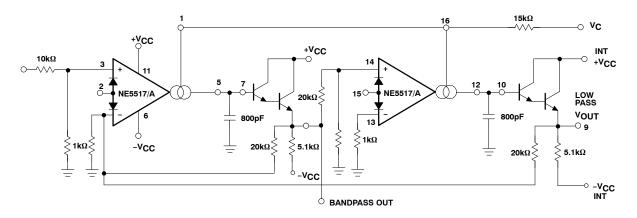


Figure 31. State Variable Filter

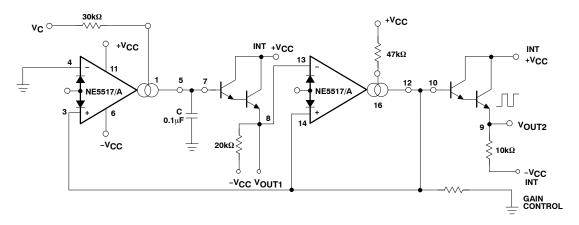


Figure 32. Triangle-Square Wave Generator (VCO)

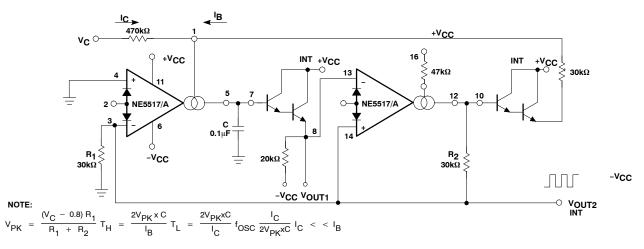


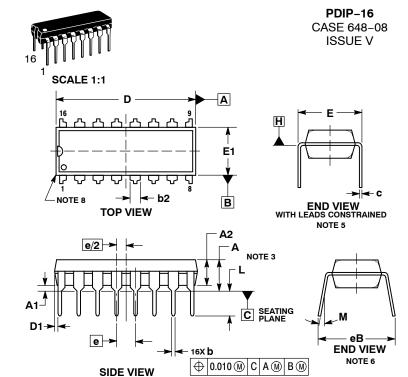
Figure 33. Sawtooth Pulse VCO

#### **ORDERING INFORMATION**

Device	Temperature Range	Package	Shipping <sup>†</sup>	
AU5517DR2		SOIC-16		
AU5517DR2G	−40 to +125 °C	SOIC-16 (Pb-Free)	2500 Tape & Reel	
NE5517D		SOIC-16		
NE5517DG		SOIC-16 (Pb-Free)	48 Units/Rail	
NE5517DR2		SOIC-16		
NE5517DR2G		SOIC-16 (Pb-Free)	2500 Tape & Reel	
NE5517N	0 to +70 °C	PDIP-16		
NE5517NG		PDIP-16 (Pb-Free)		
NE5517AN		PDIP-16	25 Units/Rail	
NE5517ANG	1	PDIP-16 (Pb-Free)		

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

Intel is a registered trademark of Intel Corporation in the U.S. and/or other countries.



STYLE 1: STYLE 2: PIN 1. COMMON DRAIN CATHODE CATHODE PIN 1. 2. 2. з. CATHODE 3. COMMON DRAIN COMMON DRAIN 4. 5. CATHODE 4. CATHODE 5. 6. CATHODE 6. COMMON DRAIN 7. CATHODE 7. COMMON DRAIN COMMON DRAIN CATHODE 8. 9. 8. 9. ANODE GATE 10. ANODE 10. SOURCE ANODE ANODE 11. 12. GATE 11. SOURCE 12. 13. ANODE 13. GATE 14. 15. ANODE ANODE 14. 15. SOURCE GATE 16. ANODE 16. SOURCE

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2
- 3.
- DIMENSIONING AND TOLERANGURA PER ASIME T14.500, 1994. CONTROLLING DIMENSION: INCHES. DIMENSIONS A, A1 AND L ARE MEASURED WITH THE PACK-AGE SEATED IN JEDEC SEATING PLANE GAUGE GS-3. DIMENSIONS D, D1 AND E1 DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS. MOLD FLASH OR PROTRUSIONS ARE NOT TO EXCEED 0.10 INCH. 4.
- DIMENSION E IS MEASURED AT A POINT 0.015 BELOW DATUM PLANE H WITH THE LEADS CONSTRAINED PERPENDICULAR 5. TO DATUM C.
- DIMENSION OF IS MEASURED AT THE LEAD TIPS WITH THE 6.
- LEADS UNCONSTRAINED. DATUM PLANE H IS COINCIDENT WITH THE BOTTOM OF THE 7
- LEADS, WHERE THE LEADS EXIT THE BODY. PACKAGE CONTOUR IS OPTIONAL (ROUNDED OR SQUARE 8 CORNERS).

	INCHES		MILLIMETER		
DIM	MIN	MAX	MIN	MAX	
Α		0.210		5.33	
A1	0.015		0.38		
A2	0.115	0.195	2.92	4.95	
b	0.014	0.022	0.35	0.56	
b2	0.060	) TYP	1.52 TYP		
С	0.008	0.014	0.20	0.36	
D	0.735	0.775	18.67	19.69	
D1	0.005		0.13		
Е	0.300	0.325	7.62	8.26	
E1	0.240	0.280	6.10	7.11	
е	0.100 BSC		2.54	BSC	
eВ		0.430		10.92	
Г	0.115	0.150	2.92	3.81	
Μ		10°		10°	

GENERIC **MARKING DIAGRAM\*** 

<sup>16</sup> <u> </u>
XXXXXXXXXXXXX
O AWLYYWWG
᠋ᡃᢧ᠋ᢑ᠋᠊ᠥᢑᢑᢑᢑᡆᡃ

XXXXX = Specific Device Code

- = Assembly Location
- WL = Wafer Lot

А

- YY = Year
- WW = Work Week
- G = Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " .", may or may not be present.

DOCUMENT NUMBER:	98ASB42431B	Electronic versions are uncontrolled except when accessed directly from the Printed versions are uncontrolled except when stamped "CONTROLLED Controlled except when stamped "CONTROLLED Control of the statement		
DESCRIPTION:	PDIP-16		PAGE 1 OF 1	
ON Semiconductor reserves the right the suitability of its products for any pa	ON Semiconductor and III are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.			



DATE 22 APR 2015





DIMENSIONS: MILLIMETERS

DOCUMENT NUMBER:	98ASB42566B	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	PTION: SOIC-16 PAGE 1 OF		PAGE 1 OF 1	
ON Semiconductor and a retrademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the				

onsemi, ONSEMI, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi** products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by **onsemi**. "Typical" parameters which may be provided in **onsemi** data sheets and/or specifications can and do vary in different applications and calcular performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. **onsemi** does not convey any license under any of its intellectual property rights nor the rights of others. **onsemi** products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use **onsemi** products for any such unintended or unauthorized application, Buyer shall indemnify and hold **onsemi** and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that **onsemi** was negligent regarding the design or manufacture of the part. **onsemi** is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### PUBLICATION ORDERING INFORMATION

#### LITERATURE FULFILLMENT:

#### TECHNICAL SUPPORT

onsemi Website: www.onsemi.com

Email Requests to: orderlit@onsemi.com

North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support: Phone: 00421 33 790 2910 For additional information, please contact your local Sales Representative

٥